

FORM PTO-892 (REV. 2-92)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		SERIAL NO. 08/416100	GROUP/ART UNIT 2212	ATTACHMENT TO PAPER NUMBER 3		
NOTICE OF REFERENCES CITED				APPLICANT(S) Prater et al.				
U.S. PATENT DOCUMENTS								
•	DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE		
A	3013467	12/61	Minsky	356	432	—		
B	4935634	6/90	Hansma et al.	250	306	—		
C	5117466	5/92	Buicon et al.	382	6	—		
D	5127730	7/92	Brelja et al.	356	318	—		
E	5164791	11/92	Kubo et al.	250	306	—		
F	5172002	12/92	Marshall	250	306	—		
G	5206702	4/93	Kato et al.	250	306	—		
H	5231286	7/93	Kajimura et al.	250	306	—		
I	5260824	11/93	Okada et al.	250	306	19 April '90		
J	5291775	3/94	Gamble et al.	73	105	04 March '92		
K	5298975	3/94	Khoury et al.	73	105	27 Sept. '91		
FOREIGN PATENT DOCUMENTS								
•	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUB-CLASS	PERTINENT SHTS. DWG.	PP. SPEC.
L	698194	11/64	Canada	Dreyfus	73	105		
M								
N								
O								
P								
Q								
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)								
R	Hipp et al., "A Stand-Alone Scanning Force and Friction Microscope", Ultramicroscopy, 42-44, 1992, pp. 1498-1503.							
S	Baselt et al., "Scanned-Cantilever Atomic Force Microscope", Rev. Sci. Instrum., 64(4), April 1993, pp. 908-911.							
T	Clark et al., "A High Performance Scanning Force Microscope Head Design", Rev. Sci. Instrum., 64(4), April 1993, pp. 904-907.							
U								
EXAMINER		DATE						
		13 July 1995						
* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05 (a).)								

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NOTICE OF REFERENCES CITED				APPLICANT(S) <i>Prater et al.</i>										
U.S. PATENT DOCUMENTS														
*		DOCUMENT NO.						DATE	NAME	CLASS	SUB-CLASS	FILING DATE IF APPROPRIATE		
A		5	3	8	8	4	5	2	2/95	<i>Harp et al.</i>	73	105	15 Oct. '93	
B		5	3	9	4	7	4	1	3/95	<i>Kajimura et al.</i>	73	105	27 April '93	
C		5	4	0	6	8	3	3	4/95	<i>Yamamoto</i>	73	105	13 Aug. '93	
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FOREIGN PATENT DOCUMENTS														
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R		<i>Jung et al., "Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens", Electronic Letters, Vol. 29, No. 3,</i>												
S		<i>February 1993, pp. 264-266.</i>												
T		<i>Martin et al., "Atomic Force Microscope-Force Mapping and Profiling on a Sub 100-Å Scale", J. Appl. Phys., 61(10), 15 May 1987, 4723-4729.</i>												
U		<i>van der Werf et al., "Compact Stand-Alone Atomic Force Microscope", Rev. Sci. Instrum., 64(10), October 1993, pp. 2892-2897.</i>												
EXAMINER		DATE												
<i>David J. Hill</i>		<i>13 July 1995</i>												
* A copy of this reference is not being furnished with this office action. (See Manual of Patent Examining Procedure, section 707.05 (a).)														